

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

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CN #:W1905-01DATE:13-Jun-2019MEANS OF DISTINGUISHING CHANGED DEVICES:				NGED DEVICES:
Product Affected: Refer to attachmen Date Effective: 13-Sep-2019	t 2	 Product Mark Back Mark Date Code Other 		e Fab location is the 2 digit sequential te code line of the top
*		A the alarmants	Vaa	
Contact: IDT PCN DESK		Attachment:	Yes	D No
E-mail: pcndesk@idt.com		Samples: Please con sample re		es representative for
DESCRIPTION AND PURPOSE OF C	CHANGE:			
 Die Technology Wafer Fabrication Process Assembly Process Equipment Material Testing Manufacturing Site Data Sheet Other 	ation Process beess as an alternate Foundry for the products listed on this notice. This is to provide additional manufacturing capacity for these products. There is no change to the product design or process technology as the existing qualified Foundry, TSMC Fab 8.			
		quantitation report		
RELIABILITY/QUALIFICATION SU Based on wafer and component level qu reliability of the product.		racterization tests, ther	e is no change to th	e performance or
CUSTOMER ACKNOWLEDGMENT IDT records indicate that you require we to grant approval or request additional in it will be assumed that this change is acc IDT reserves the right to ship either vers on the earlier version has been depleted.	ritten notification of this channels in the second	t receive acknowledge	ment within 30 day	s of this notice
Customer:	C] Approval for s	shipments prior	to effective date.
Name/Date:	E	-Mail Address:		
Title:	P	hone#/Fax#:		
CUSTOMER COMMENTS:				
IDT ACKNOWLEDGMENT OF REC	CEIPT:			
RECD. BY:		DATE:		



Qualification Report

Device Family:	AW670T	Process Technology:	CM018HV, 1P4M
Package Type:	NDG48 (VFQFPN)	Fab Location:	TSMC Fab 6

Test Description	Standard	Test Conditions	Sample Size	Reject	Comments
Device Characterization	IDT's datasheet condition		80	0	Pass
ESD: Human Body Model	JESD22-A114 (JS-001) Classification – 1B	1 KV	3	0	Pass 1KV
ESD: Charged Device Model	JESD22-C101 Classification – C1	500 V	3	0	Pass 500V
Latch-Up	JESD78	+/-100mA I/O and 1.5x Vcc OV stress, Class II (85°C)	3	0	Pass
Early Life Failure Rate (ELFR)	JESD22-A108, JESD74	48 hrs. @ 125 °C, Vcc = 20V	834	0	Pass
High Temperature Operating Life (HTOL)	JESD22-A108, +125°C, Vcc-max	1,000 hrs. @ 125 °C, Vcc =20V	77	0	Pass
High Temperature Storage (HTS)	JESD22-A103	150°C, 1000 hrs	77	0	Pass



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ATTACHMENT 2 - PCN # : W1905-01

Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
P9235A-0NDGI	P9235A-B0NDGI8	P9236A-B0NDGI	P9242-RBNDGI/B
P9235A-0NDGI8	P9235A-RBNDGI	P9236A-B0NDGI8	P9242-RBNDGI8
P9235A-16NDGI	P9235A-RBNDGI8	P9236A-B1NDGI	P9242-RBNDGI8/B
P9235A-16NDGI8	P9235A-RNDGI	P9236A-B1NDGI8	P9242-RNDGI
P9235A-18NDGI	P9235A-RNDGI8	P9242-R0NDGI	P9242-RNDGI8
P9235A-18NDGI8	P9236A-0NDGI	P9242-R0NDGI8	
P9235A-B0NDGI	P9236A-0NDGI8	P9242-RBNDGI	